

**Search Notes****Application/Control No.**

10/712,643

**Examiner**

Ted M. Wang

**Applicant(s)/Patent under Reexamination**

FAN ET AL.

**Art Unit**

2611

**SEARCHED**

Class	Subclass	Date	Examiner
375	136, 142, 152	6/2/2008	TW
375	153, 316	6/2/2008	TW
	UPDATED		
375	147	6/2/2008	TW

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
375	147, 136	6/2/2008	TW
375	142, 152	6/2/2008	TW
375	153, 316	6/2/2008	TW

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST - USPGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB, see attached search report	6/2/2008	TW
ODP- searched and reviewed from EAST and PALM	6/2/2008	TW
IEEEExplor- Author- Fan Y. P. Hwang S. M. Li H. Y. Chao C. Y.	6/2/2008	TW
IEEEExplor- Advance -despread\$3 and in-phase and quadrature and insert* zero and initial condition	6/2/2008	TW